Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/812,986	JUNG, YUN-HO
Examiner	Art Unit
Stephen W. Smoot	2813

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	SEARCHED			
Class	Subclass	Date	Examiner	
219	121.6	2/18/2005	sws	
250	492.22	2/18/2005	SWS.	
257	75	2/18/2005	sws	
257	E21.134	2/18/2005	sws	
430	5	2/18/2005	sws	
438	487	2/18/2005	sws	
438	943	2/18/2005	sws	
438	946	2/18/2005	sws	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1		<u> </u>	

SEARCH NOT (INCLUDING SEARCH		")
	DATE	EXMR
Key Words: Sequential Lateral Solidification - SLS, Crystallization, Grain Growth;	2/18/2005	L.W.S sws
Amorphous Silicon; Polysilicon; Mask; Laser.	2/18/2005	S.W.S sws
		0410
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	2/18/2005	A.W.A. sws